

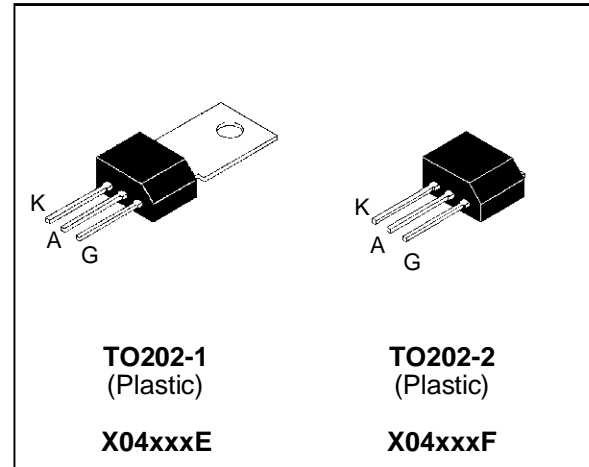
SENSITIVE GATE SCR

FEATURES

- $I_{T(RMS)} = 4A$
- $V_{DRM} = 200V$ to $800V$
- Low $I_{GT} < 200\mu A$

DESCRIPTION

The X04xxxE/F series of SCRs uses a high performance TOP GLASS PNP technology. These parts are intended for general purpose applications where low gate sensitivity is required.



ABSOLUTE RATINGS (limiting values)

| Symbol | Parameter | | Value | Unit |
|--------------------|---|------------------------------|----------------------------|------------|
| $I_{T(RMS)}$ | RMS on-state current (180° conduction angle) | X04xxxE/F $T_c = 90^\circ C$ | 4 | A |
| | | X04xxxF $T_a = 25^\circ C$ | 1.35 | |
| $I_{T(AV)}$ | Mean on-state current (180° conduction angle) | X04xxxE/F $T_c = 90^\circ C$ | 2.5 | A |
| | | X04xxxF $T_a = 25^\circ C$ | 0.9 | |
| I_{TSM} | Non repetitive surge peak on-state current (T_j initial = $25^\circ C$) | $t_p = 8.3$ ms | 33 | A |
| | | $t_p = 10$ ms | 30 | |
| I^2t | I^2t Value for fusing | $t_p = 10$ ms | 4.5 | A^2s |
| di/dt | Critical rate of rise of on-state current $I_G = 10$ mA $di_G/dt = 0.1$ A/ μs . | | 50 | A/ μs |
| T_{stg} T_j | Storage and operating junction temperature range | | - 40, + 150 - 40, + 125 | $^\circ C$ |
| TI | Maximum lead temperature for soldering during 10s at 4.5mm from case | | 260 | $^\circ C$ |

| Symbol | Parameter | Voltage | | | | Unit |
|------------------------|--|---------|-----|-----|-----|------|
| | | B | D | M | N | |
| V_{DRM} V_{RRM} | Repetitive peak off-state voltage $T_j = 125^\circ C$ $R_{GK} = 1K\Omega$ | 200 | 400 | 600 | 800 | V |

X04xxxE/F

THERMAL RESISTANCES

| Symbol | Parameter | Value | Unit | |
|----------|-------------------------|---------|------|------|
| Rth(j-a) | Junction to ambient | X04xxxE | 80 | °C/W |
| | | X04xxxF | 100 | |
| Rth(j-c) | Junction to case for DC | 7.5 | °C/W | |

GATE CHARACTERISTICS (maximum values)

$P_G (AV) = 0.2 \text{ W}$ $P_{GM} = 3 \text{ W}$ ($t_p = 20 \mu\text{s}$) $I_{GM} = 1.2 \text{ A}$ ($t_p = 20 \mu\text{s}$)

ELECTRICAL CHARACTERISTICS

| Symbol | Test Conditions | Sensitivity | | | Unit | |
|--------------------------------------|--|------------------------|-----|-----|------|------|
| | | 02 | 03 | 05 | | |
| I _{GT} | V _D =12V (DC) R _L =140Ω | T _j = 25°C | MIN | 20 | 20 | μA |
| | | | MAX | 200 | 50 | |
| V _{GT} | V _D =12V (DC) R _L =140Ω | T _j = 25°C | MAX | 0.8 | | V |
| V _{GD} | V _D =V _{DRM} R _L =3.3kΩ R _{GK} = 1 KΩ | T _j = 125°C | MIN | 0.1 | | V |
| V _{RGM} | I _{RG} = 10μA | T _j = 25°C | MIN | 8 | | V |
| t _{gd} | V _D =V _{DRM} I _{TM} = 3 x I _{T(AV)} dI _G /dt = 0.1A/μs I _G = 10mA | T _j = 25°C | MAX | 2 | | μs |
| I _H | I _T = 50mA R _{GK} = 1 KΩ | T _j = 25°C | MAX | 5 | | mA |
| I _L | I _G =1mA R _{GK} = 1 KΩ | T _j = 25°C | MAX | 6 | | mA |
| V _{TM} | I _{TM} = 8A t _p = 380μs | T _j = 25°C | MAX | 1.8 | | V |
| I _{DRM} I _{RRM} | V _D = V _{DRM} R _{GK} = 1 KΩ V _R = V _{RRM} | T _j = 25°C | MAX | 5 | | μA |
| | | T _j = 110°C | MAX | 200 | | |
| dV/dt | V _D =67%V _{DRM} R _{GK} = 1 KΩ | T _j = 110°C | MIN | | 10 | V/μs |
| | | | TYP | 15 | 15 | |
| t _q | I _{TM} = 3 x I _{T(AV)} V _R =35V dI/dt=10A/μs t _p =100μs dV/dt=2V/μs V _D = 67%V _{DRM} R _{GK} = 1 KΩ | T _j = 110°C | MAX | 50 | | μs |

ORDERING INFORMATION

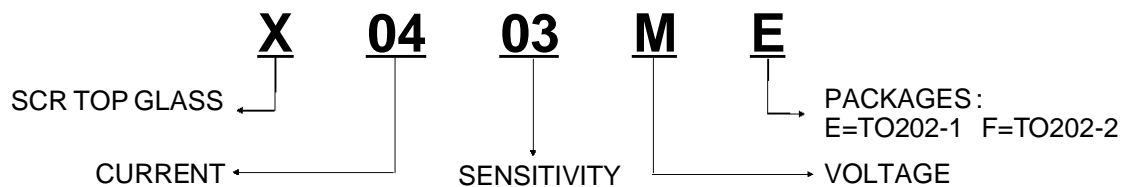


Fig.1 : Maximum average power dissipation versus average on-state current (TO202-1).

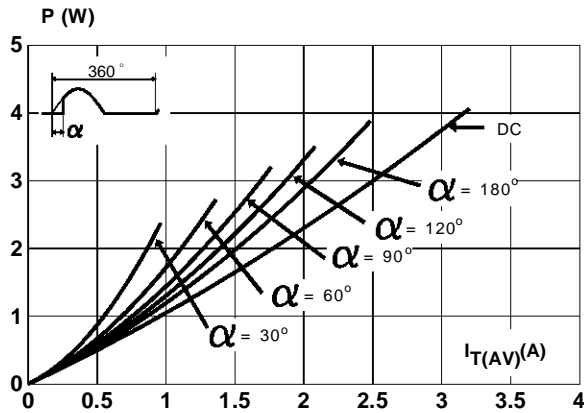


Fig.3 : Maximum average power dissipation versus average on-state current (TO202-2).

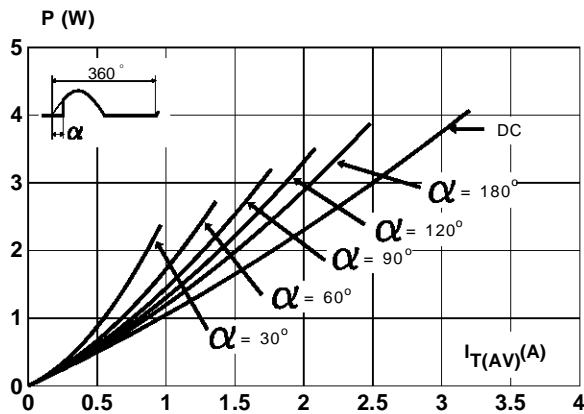


Fig.5 : Average on-state current versus case temperature (TO202-1).

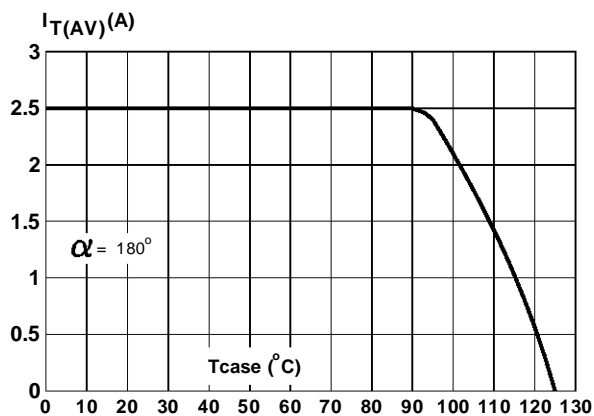


Fig.2 : Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tcase) for different thermal resistances heatsink + contact (TO202-1).

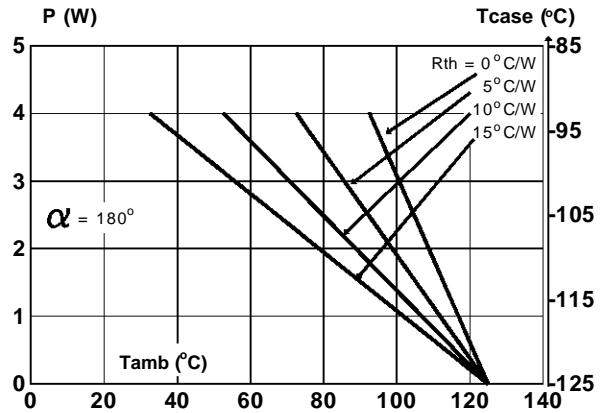


Fig.4 : Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tcase) (TO202-2).

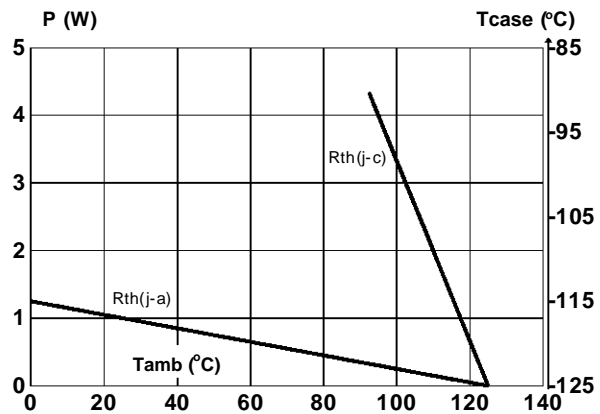


Fig.6 : Average on-state current versus case temperature (TO202-2).

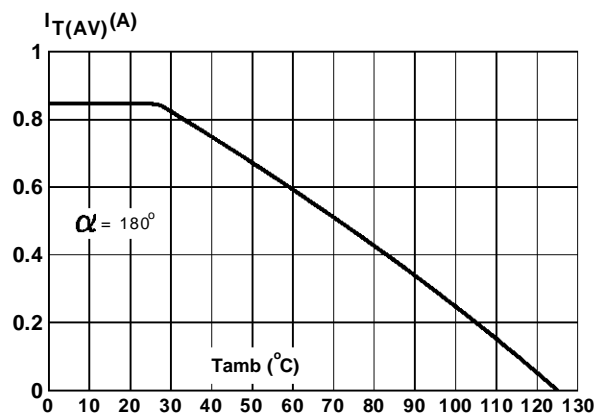


Fig.7 : Relative variation of thermal impedance versus pulse duration (TO202-1).

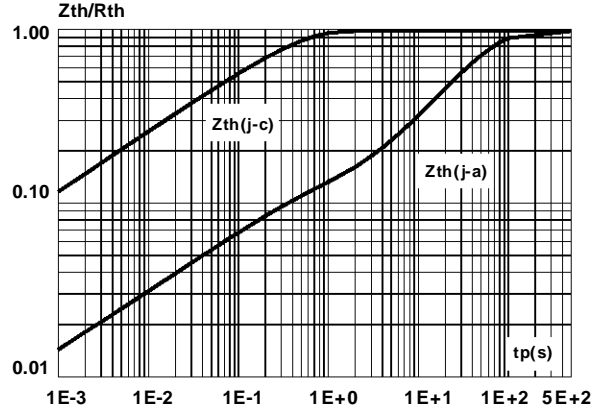


Fig.8 : Relative variation of thermal impedance junction to ambient versus pulse duration (TO202-2).

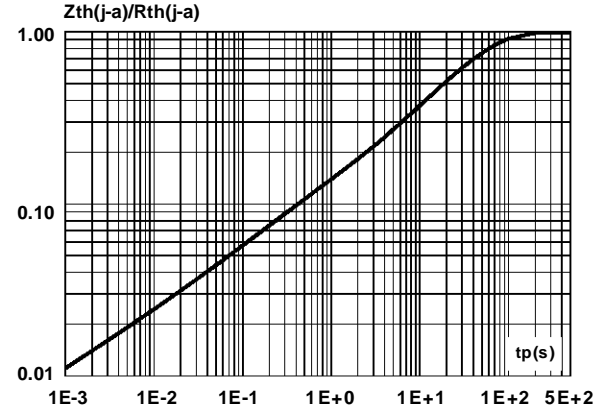


Fig.9 : Relative variation of gate trigger current and holding current versus junction temperature.

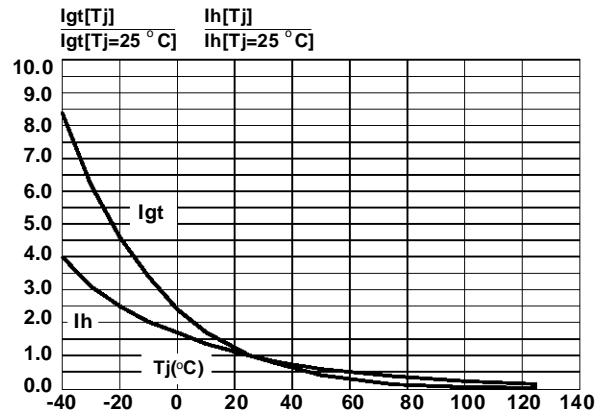


Fig.10 : Non repetitive surge peak on-state current versus number of cycles.

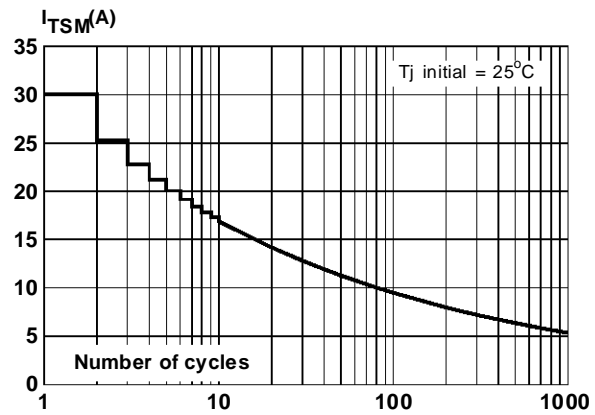


Fig.11 : Non repetitive surge peak on-state current for a sinusoidal pulse with width : $tp \leq 10ms$, and corresponding value of I^2t .

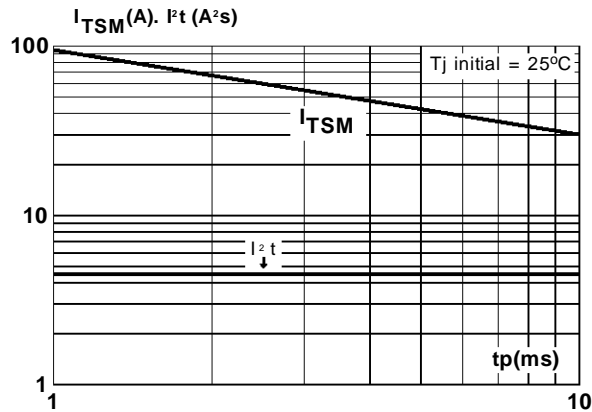
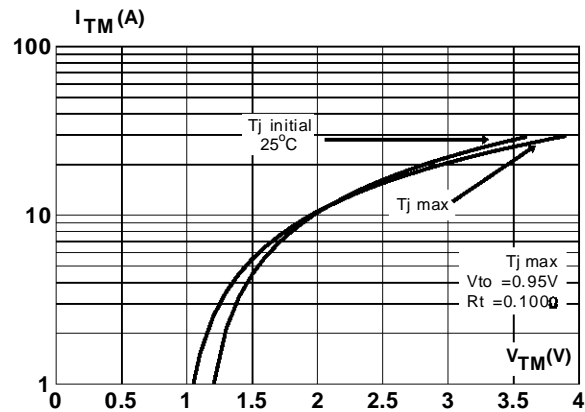


Fig.12 : On-state characteristics (maximum values).



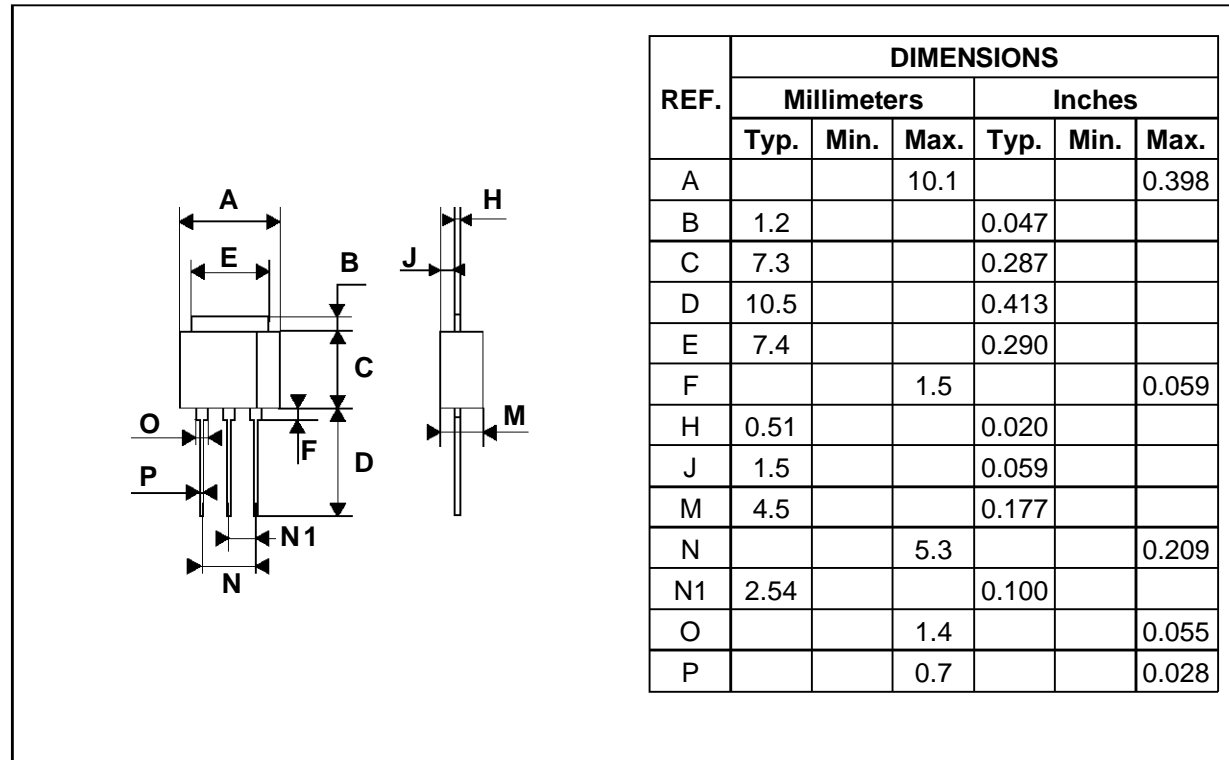
PACKAGE MECHANICAL DATA
TO202-1 (Plastic)

| REF. | DIMENSIONS | | | | | |
|------|-------------|------|------|--------|-------|-------|
| | Millimeters | | | Inches | | |
| | Typ. | Min. | Max. | Typ. | Min. | Max. |
| A | | | 10.1 | | | 0.398 |
| B | 13.7 | | | 0.540 | | |
| C | 7.3 | | | 0.287 | | |
| D | 10.5 | | | 0.413 | | |
| F | | | 1.5 | | | 0.059 |
| G | 3.2 | | | 0.126 | | |
| H | 0.51 | | | 0.020 | | |
| I | | 3.16 | 3.20 | | 0.124 | 0.126 |
| J | 1.5 | | | 0.059 | | |
| M | 4.5 | | | 0.177 | | |
| N | | | 5.3 | | | 0.209 |
| N1 | 2.54 | | | 0.100 | | |
| O | | | 1.4 | | | 0.055 |
| P | | | 0.7 | | | 0.028 |

Marking : type number
Weight : 1.4 g

X04xxxE/F

PACKAGE MECHANICAL DATA
TO202-2 (Plastic)



Marking : type number
Weight : 1.0 g

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